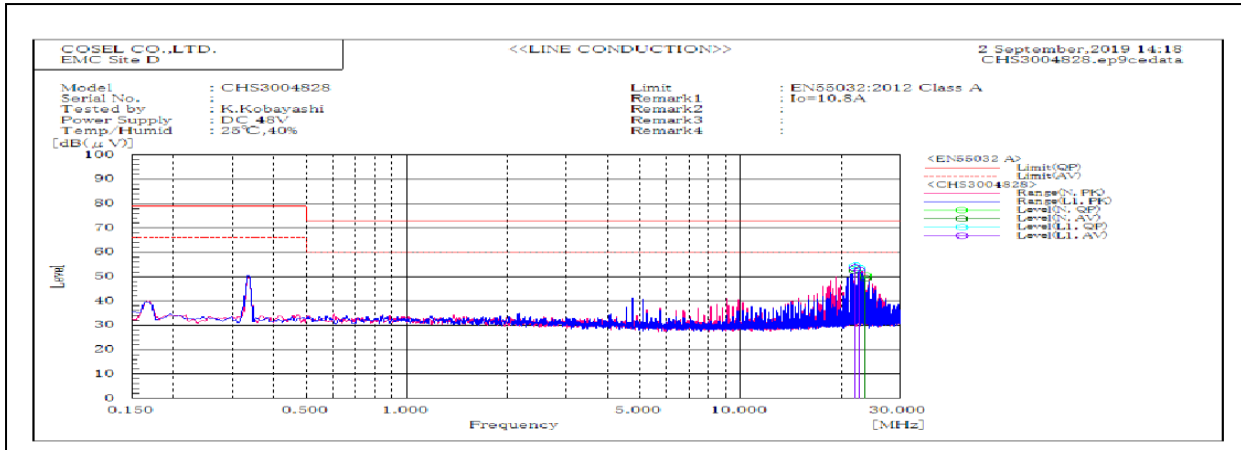
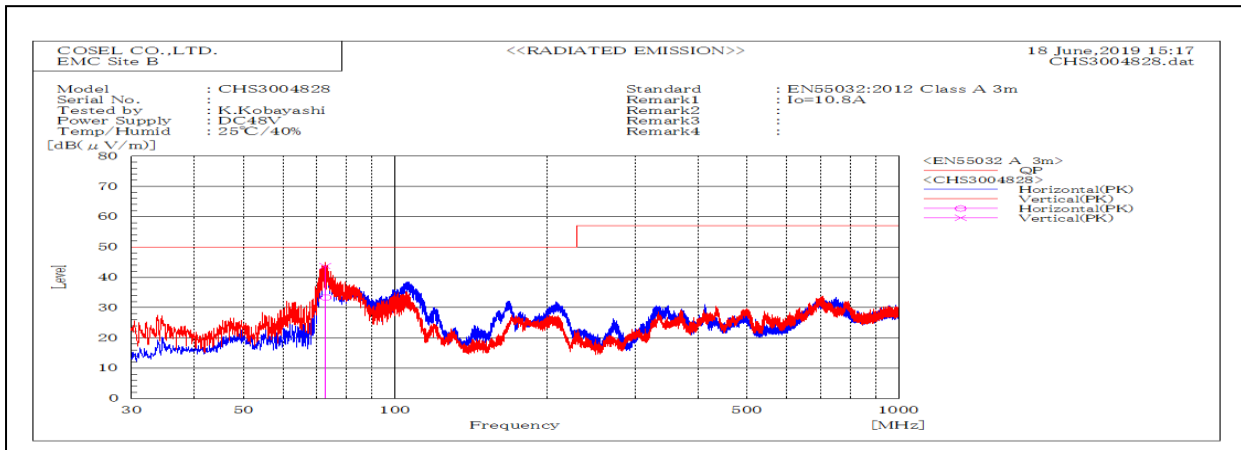


DATA SHEET		Date	02-Sep-19
Model	CHS3004828	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi



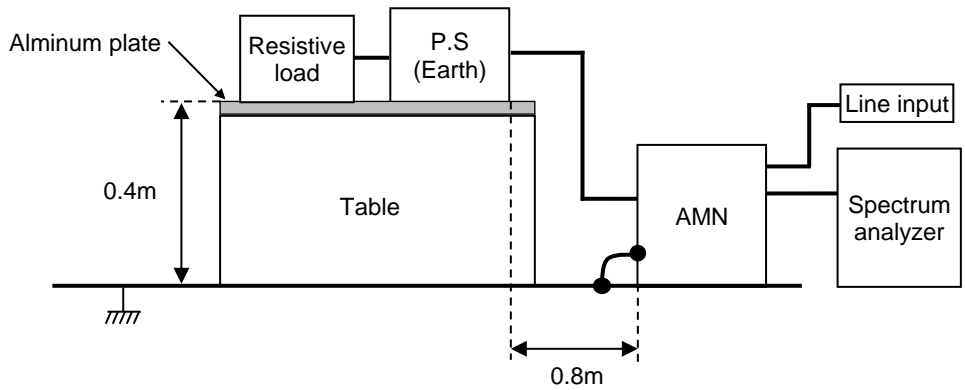
Frequency MHz	Line	Level		Limit		Margin		Pass/Fail	Remark
		dB(µV)		dB(µV)		dB			
		QP	AV	QP	AV	QP	AV		
22.01	N	53.3	52.4	73.0	60.0	19.7	7.6	Pass	
23.71	N	50.5	49.4	73.0	60.0	22.5	10.6	Pass	
22.01	L1	54.5	53.6	73.0	60.0	18.5	6.4	Pass	
22.69	L1	53.5	52.5	73.0	60.0	19.5	7.5	Pass	



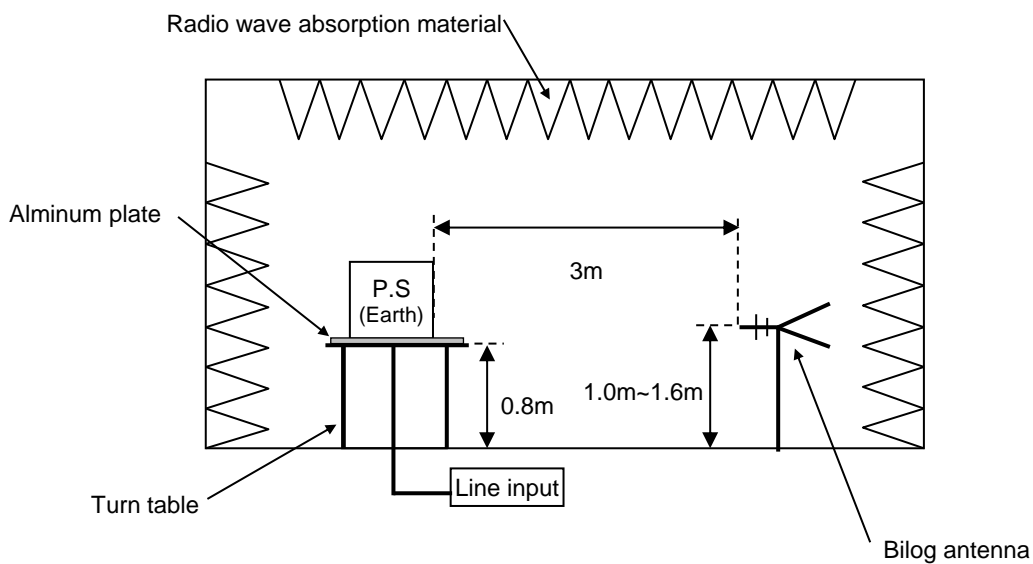
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m)	dB(uV/m)	dB				
			QP	QP	QP				
72.96	H	Stable	33.3	50.0	16.7	Pass	135.3	10.8	
72.81	V	Stable	43.7	50.0	6.3	Pass	100.2	0.0	

DATA SHEET		Date	02-Sep-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
 Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

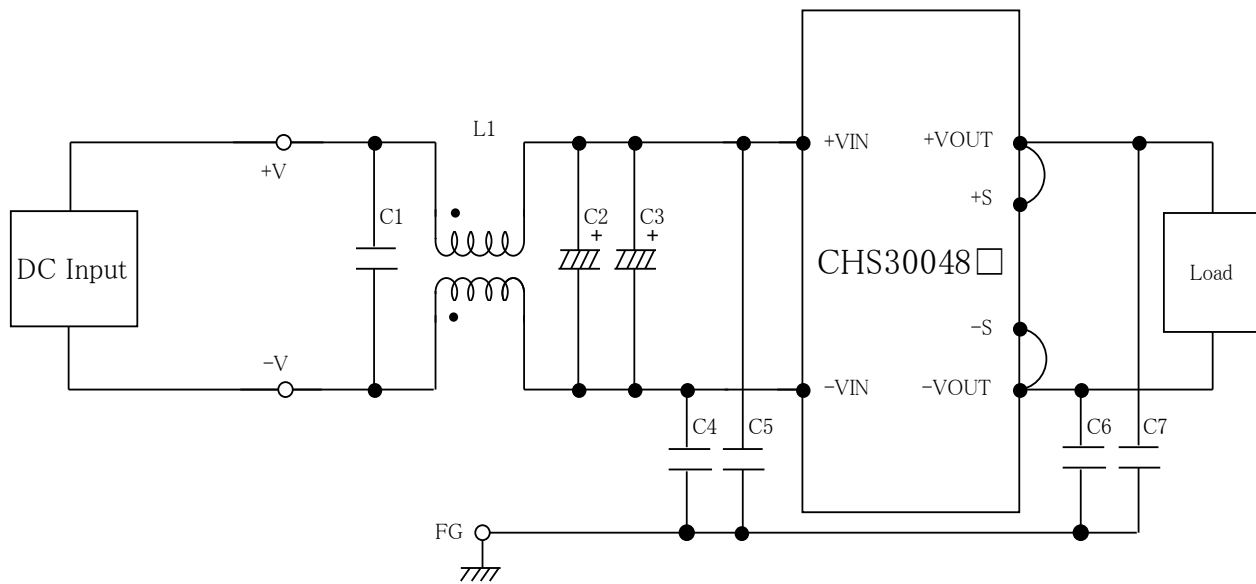


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C3 : 100V 100 μ F PWseries (nichicon)
- C4,C5 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C6,C7 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)